



Features

- Advanced Process Technology
- Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

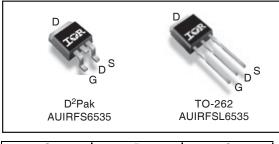
HEXFET® Power MOSFET



V _{(BR)DSS}	300V
R _{DS(on)} typ.	148m Ω
max.	185m Ω
I _D	19A

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



G	D	S
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Standard Pack		Orderable Part Number
		Form	Quantity			
AUIRFSL6535	TO-262	Tube	50	AUIRFSL6535		
AUIRFS6535	D2Pak	Tube	50	AUIRFS6535		
		Tape and Reel Left	800	AUIRFS6535TRL		
		Tape and Reel Right	800	AUIRFS6535TRR		

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T_A) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	19	
I _D @ T _C = 100°C	Continuous Drain Current, VGS @ 10V	13	Α
I _{DM}	Pulsed Drain Current ①	100	
P _D @T _C = 25°C	Power Dissipation	210	W
	Linear Derating Factor	1.4	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ©	216	mJ
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ®	310	
I _{AR}	Avalanche Current ①	See Fig.12a, 12b, 15, 16	Α
E _{AR}	Repetitive Avalanche Energy ^⑤		mJ
TJ	Operating Junction and	-55 to +175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

	Parameter	Тур.	Max.	Units
R₀Jc	Junction-to-Case ®		0.71	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ⑦		40	

HEXFET® is a registered trademark of International Rectifier.

^{*}Qualification standards can be found at http://www.irf.com/



Static Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions			
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	300			V	$V_{GS} = 0V, I_D = 250\mu A$			
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.39		V/°C	Reference to 25°C, I _D = 5.0mA			
R _{DS(on)}	Static Drain-to-Source On-Resistance		148	185	mΩ	V _{GS} = 10V, I _D = 11A ③			
$V_{GS(th)}$	Gate Threshold Voltage	3.0		5.0	V	$V_{DS} = V_{GS}$, $I_D = 150\mu A$			
gfs	Forward Transconductance	15			V	$V_{DS} = 50V, I_{D} = 11A$			
I _{DSS}	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 300V, V_{GS} = 0V$			
				250		$V_{DS} = 300V, V_{GS} = 0V, T_{J} = 125^{\circ}C$			
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$			
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$			

Dynamic Electrical @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
Q_g	Total Gate Charge		38	57		I _D = 11A
Q_{gs}	Gate-to-Source Charge		12		nC	$V_{DS} = 150V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		13			V _{GS} = 10V ③
t _{d(on)}	Turn-On Delay Time		15			$V_{DD} = 300V$
t _r	Rise Time		16			I _D = 11A
t _{d(off)}	Turn-Off Delay Time		22		ns	$R_G = 5.0\Omega$
t _f	Fall Time		10			V _{GS} = 10V ③
L_D	Internal Drain Inductance		4.5			Between lead,
					nΗ	6mm (0.25in.)
Ls	Internal Source Inductance		7.5			from package
						and center of die contact
C _{iss}	Input Capacitance		2340			$V_{GS} = 0V$
Coss	Output Capacitance		195			$V_{DS} = 25V$
Crss	Reverse Transfer Capacitance		40		рF	f = 1.0MHz
Coss	Output Capacitance		1750			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
Coss	Output Capacitance		66			$V_{GS} = 0V, V_{DS} = 240V, f = 1.0MHz$
Coss eff.	Effective Output Capacitance		130			V_{GS} = 0V, V_{DS} = 0V to 240V \oplus

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			19		MOSFET symbol
	(Body Diode)				Α	showing the
I_{SM}	Pulsed Source Current			100		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 11A$, $V_{GS} = 0V$ ³
t _{rr}	Reverse Recovery Time		190	285	ns	$T_J = 25^{\circ}C$, $I_F = 11A$, $V_{DD} = 150V$
Q _{rr}	Reverse Recovery Charge		990	1485	nC	di/dt = 100A/μs ③
t _{on}	Forward Turn-On Time	Intrinsic	Intrinsic turn-on time is negligible (turn-on is abminated by LS+LD)			

Notes:

- Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by T_{Jmax} , starting $T_{J}=25^{\circ}C$, L=3.6mH $R_{G}=50\Omega$, $I_{AS}=11A$, $V_{GS}=10V$. Part not recommended for use above this value.
- $\ \ \, \Phi \ \ \, C_{oss}$ eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- S Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ® This value is determined from sample failure population, starting $T_J = 25^{\circ}C$, L = 3.6mH, $R_G = 50Ω$, $I_{AS} = 11A$, $V_{GS} = 10V$.

- This is applied to D²Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.



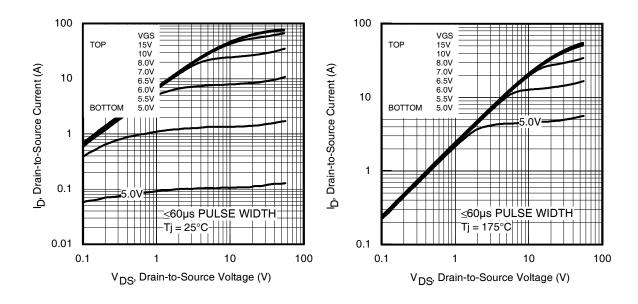


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

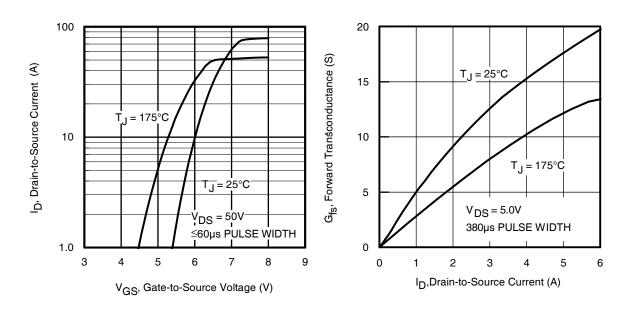
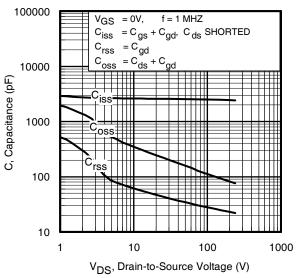


Fig 3. Typical Transfer Characteristics

Fig 4. Typical Forward Transconductance vs. Drain Current





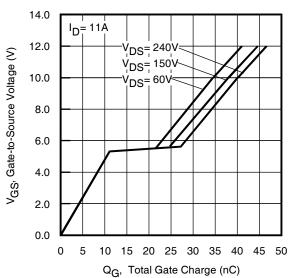
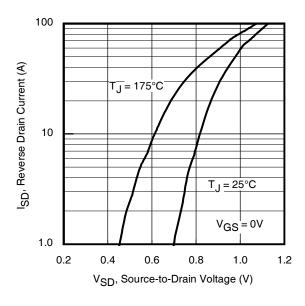


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



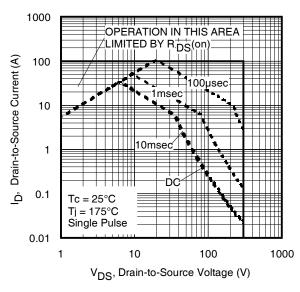


Fig 7. Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area



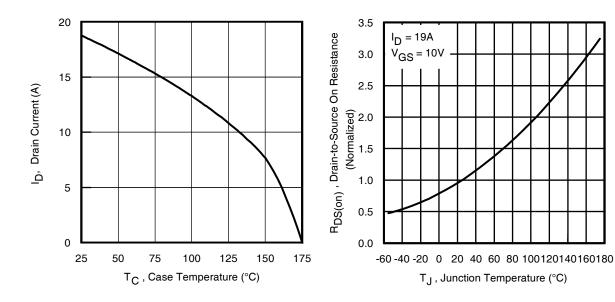


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Normalized On-Resistance vs. Temperature

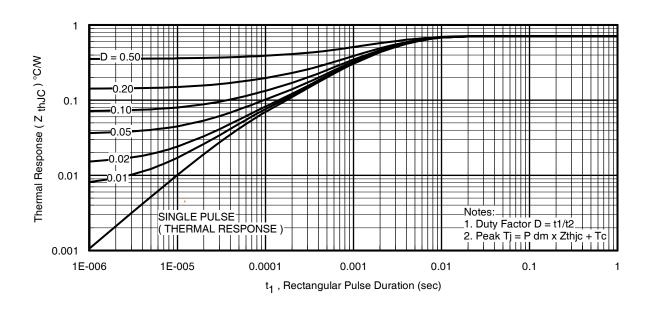


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



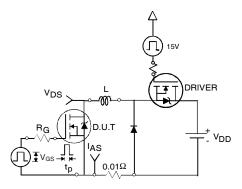


Fig 12a. Unclamped Inductive Test Circuit

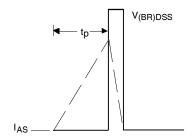


Fig 12b. Unclamped Inductive Waveforms

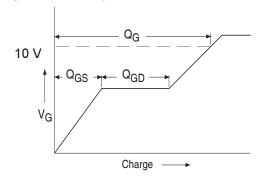


Fig 13a. Basic Gate Charge Waveform

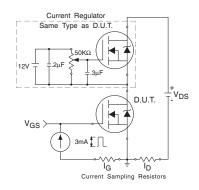


Fig 13b. Gate Charge Test Circuit

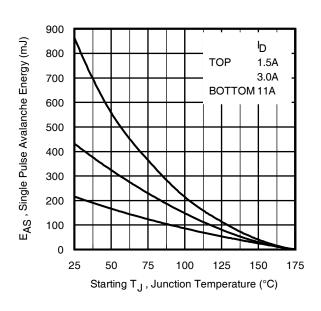


Fig 12c. Maximum Avalanche Energy vs. Drain Current

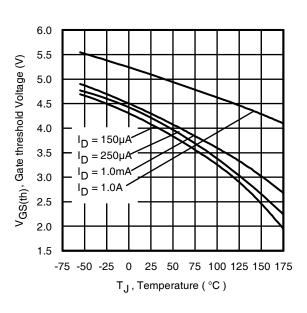


Fig 14. Threshold Voltage vs. Temperature



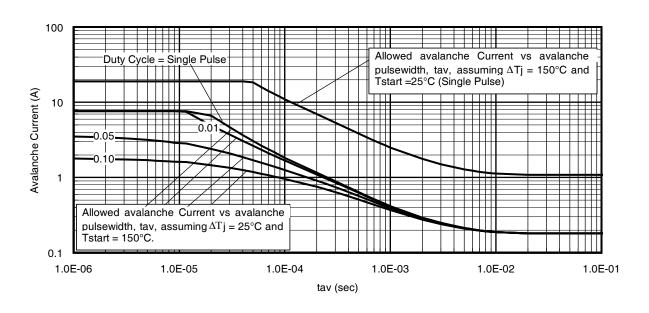


Fig 15. Typical Avalanche Current vs. Pulsewidth

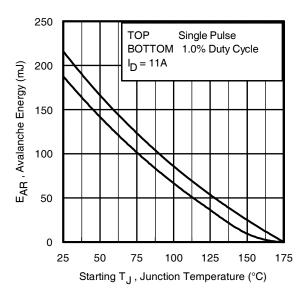


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- P_{D (ave)} = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16). t_{av} = Average time in avalanche. D = Duty cycle in avalanche = t_{av} ·f $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \; (ave)} = 1/2 \; (\; 1.3 \cdot BV \cdot I_{aV}) = \triangle T / \; Z_{thJC} \\ I_{av} = 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} = P_{D \; (ave)} \cdot t_{av} \end{split}$$



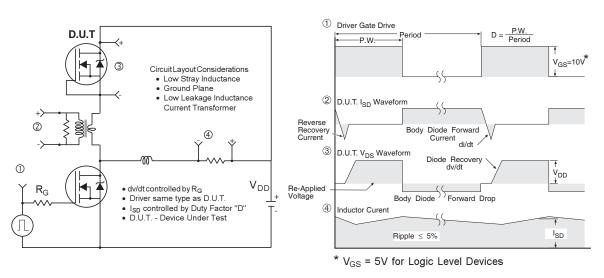


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

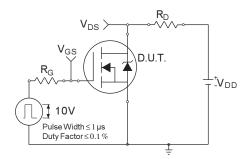


Fig 18a. Switching Time Test Circuit

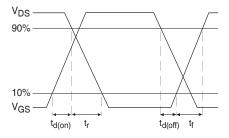
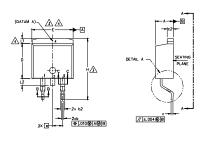


Fig 18b. Switching Time Waveforms

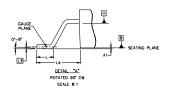


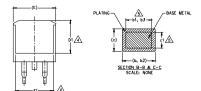
D²Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)









S M B O			N		
B	MILLIM	ETERS	INC	HES	NO TES
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1,14	1,78	.045	.070	
b3	1,14	1,73	.045	.068	5
С	0,38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270		4
Ε	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
е	2.54	BSC	.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1,65	-	.066	4
L2	-	1,78	-	.070	
L3	0.25	BSC	.010	BSC	
L4	4.78	5.28	.188	.208	

- 1, DIMENSIONING AND TOLERANCING PER ASME Y14,5M-1994
- 2. DIMENSIONS ARE SHOWN IN WILLIMETERS [INCHES].
- 3. DIMENSION D & E DD NOT INCLUDE MOLD FLASH MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 5. DIMENSION 61 AND 61 APPLY TO BASE METAL ONLY.
- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H
- 7. CONTROLLING DIMENSION: INCH.
- B. DUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

D²Pak (TO-263AB) Part Marking Information

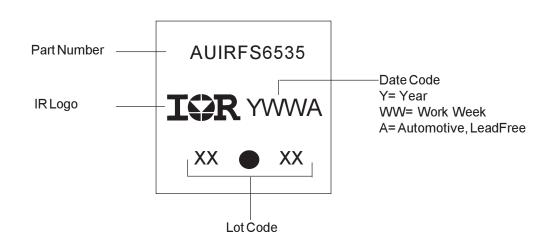
LEAD ASSIGNMENTS

DIODES

HEXFET

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

IGBTs, CoPACK

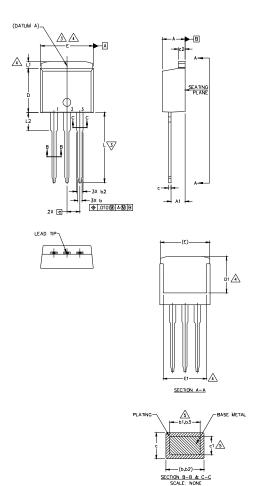


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



TO-262 Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. CONTROLLING DIMENSION; INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S			N		
M B O	MILLIM	ETERS	INC	HES	NOTES
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4,83	.160	.190	
A1	2.03	3,02	.080	,119	
ь	0.51	0.99	.020	.039	
ь1	0.51	0,89	.020	.035	5
b2	1,14	1,78	.045	.070	
b3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270	-	4
Ε	9.65	10.67	.380	.420	3,4
E1	6,22	-	.245		4
е	2.54	BSC	.100	.100 BSC	
L	13,46	14.10	,530	.555	
L1	-	1.65	-	.065	4
L2	3.56	3.71	.140	.146	

LEAD ASSIGNMENTS

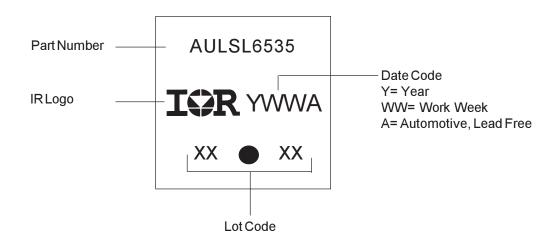
HEXFET

- 1 GATE
- 2.- DRAIN 3.- SOURCE
- 4.- DRAIN

IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

TO-262 Part Marking Information

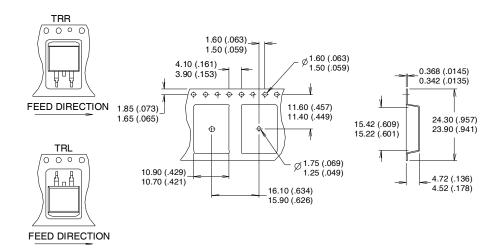


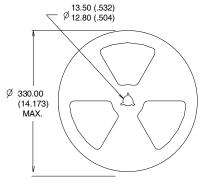
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/pkhexfet.html

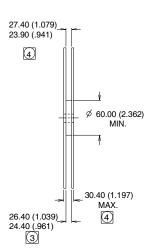


D²Pak Tape & Reel Information

Dimensions are shown in millimeters (inches)







NOTES:

- COMFORMS TO EIA-418.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION MEASURED @ HUB. INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/pkhexfet.html

11



Qualification Information[†]

Qualification Level		Automotive (per AEC-Q101)						
		Comments: qualification. granted by ex	IR's Inc	lustrial	and Consun	ner qualific		
Maiatana Oa				N/A				
Moisture Se	nsitivity Level	D ² PAK		MSL1				
	Machine Model	Class M2 (+/- 200V) ^{††}						
				AE	C-Q101-002			
	Human Body Model	Class H1B (+/- 1000V) ^{††}						
ESD		AEC-Q101-001						
	Charged Device Model	Class C5 (+/- 2000V) ^{††}						
		AEC-Q101-005						
RoHS Compliant Yes								

[†] Qualification standards can be found at International Rectifier's web site: http://www.irf.com/

^{††} Highest passing voltage.



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IR products are neither designed nor intended for use in automotive applications or environments unless the specific IR products are designated by IR as compliant with ISO/TS 16949 requirements and bear a part number including the designation "AU". Buyers acknowledge and agree that, if they use any non-designated products in automotive applications. IR will not be responsible for any failure to meet such requirements.

For technical support, please contact IR's Technical Assistance Center http://www.irf.com/technical-info/

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